

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/791,529 | Applicant(s)/Patent Under Reexamination AREH ET AL. | |
| | Examiner Bena Miller | Art Unit 3725 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-4,186,096 | 01-1980 | Areaux et al. | 210/377 |
| * | B | US-2,138,716 | 11-1938 | SHELLY TRUITT | 241/273.2 |
| * | C | US-2,552,572 | 05-1951 | MIKINA STANLEY J | 99/503 |
| * | D | US-3,753,297 | 08-1973 | Mantelet, Jean | 34/58 |
| * | E | US-4,345,517 | 08-1982 | Arao et al. | 99/511 |
| * | F | US-5,074,201 | 12-1991 | Takeyama et al. | 99/483 |
| * | G | US-5,236,135 | 08-1993 | Wilson et al. | 241/21 |
| * | H | US-3,916,776 | 11-1975 | Arao et al. | 99/503 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.